



CTLM17NS10-R3

N-Channel Enhancement MOSFET

Features

- Drain-Source Breakdown Voltage V_{DS} 100 V
- Drain-Source On-Resistance
 $R_{DS(ON)} 3\Omega$, at $V_{GS} = 10V$, $I_D = 100mA$
 $R_{DS(ON)} 3\Omega$, at $V_{GS} = 4.5V$, $I_D = 100mA$
- Continuous Drain Current at $T_A = 25^\circ C$ $I_D = 0.17A$
- Advanced high cell density Trench Technology
- RoHS Compliance & Halogen Free

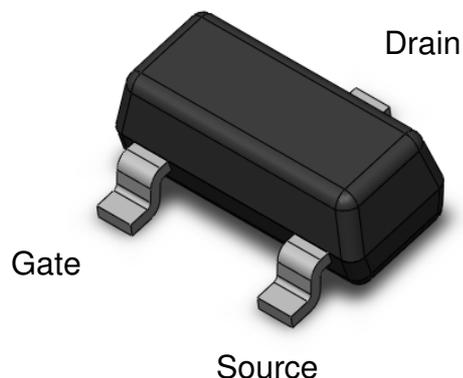
Applications

- Power Management
- LCD Display inverter
- DC/DC Converter
- Load Switch

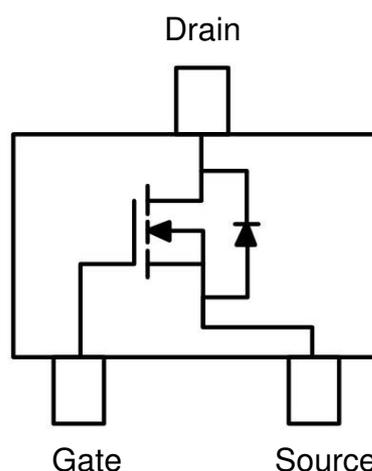
Description

The CTLM17NS10-R3 is the N-Channel logic enhancement mode power field effect transistors are produced using high cell density, DMOS trench technology. This high density process is especially tailored to minimize on-state resistance.

Package Outline



Schematic





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Absolute Maximum Rating at 25°C

Symbol	Parameters	Test Conditions	Min	Notes
V _{DS}	Drain-Source Voltage	100	V	
V _{GS}	Gate-Source Voltage	±20	V	
I _D	Continuous Drain Current @T _A =25°C	0.17	A	1
I _{DM}	Pulsed Drain Current	0.7	A	1
P _D	Total Power Dissipation @T _A =25°C	0.36	W	2
T _{STG}	Storage Temperature Range	-55 to 150	°C	
T _J	Operating Junction Temperature Range	-55 to 150	°C	

Thermal Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
R _{θJA4}	Thermal Resistance Junction-Ambient (t=10s)		--	350	--	°C /W	1,4



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Electrical Characteristics $T_A = 25^\circ\text{C}$ (unless otherwise specified)

Static Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$B_{V_{DS}}$	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A$	100	-	-	V	
I_{DSS}	Drain-Source Leakage Current	$V_{DS} = 100V, V_{GS} = 0V$	-	-	1	μA	
I_{GSS}	Gate-Source Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	± 100	nA	

On Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$R_{DS(ON)}$	Drain-Source On-Resistance	$V_{GS} = 10V, I_D = 100mA$	-	3	6	Ω	3
		$V_{GS} = 4.5V, I_D = 100mA$	-	3	10	Ω	
$V_{GS(th)}$	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250\mu A$	0.8	---	2.8	V	3

Dynamic Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
C_{ISS}	Input Capacitance	$V_{GS} = 0V,$ $V_{DS} = 25V$ $f = 1MHz$	-	42.5	-	pF	
C_{OSS}	Output Capacitance		-	14	-		
C_{RSS}	Reverse Transfer Capacitance		-	3	-		

Switching Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$T_{D(ON)}$	Turn-On Delay Time	$V_{DS} = 30V,$ $R_L = 107\Omega,$ $V_{GS} = 10V,$ $R_G = 50\Omega$	-	5.5	-	ns	
T_R	Rise Time		-	21.7	-		
$T_{D(OFF)}$	Turn-Off Delay Time		-	5.3	-		
T_F	Fall Time		-	6.4	-		
Q_G	Total Gate Charge	$V_{DS} = 10V,$ $V_{GS} = 10V,$ $I_D = 0.22A$	-	6.3	-	nC	
Q_{GS}	Gate-Source Charge		-	1.6	-		
Q_{GD}	Gate-Drain Charge		-	0.7	-		



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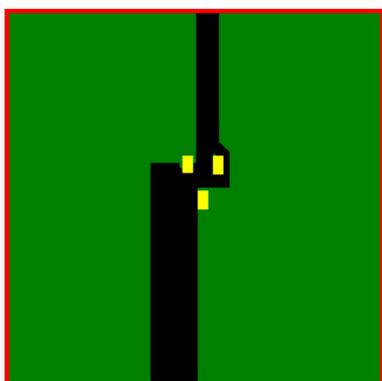
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Drain-Source Diode Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
V _{SD}	Body Diode Forward Voltage	V _{GS} = 0V, I _D = 0.34A	-	0.9	1.3	V	
I _{SD}	Body Diode Continuous Current		-	-	0.25	A	1

Note:

1. The power dissipation is limited by 150°C junction temperature.
2. Device mounted on a glass-epoxy board



FR-4
25.4 × 25.4 mm .
2 Oz Copper

Actual Size

3. The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
4. Thermal Resistance follow JESD51-3.



Typical Characteristic Curves

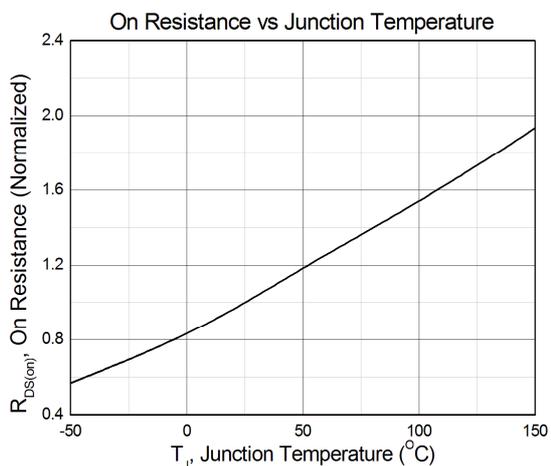


Figure 1

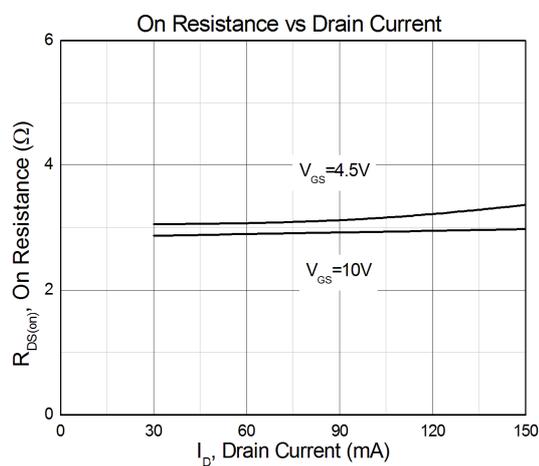


Figure 2

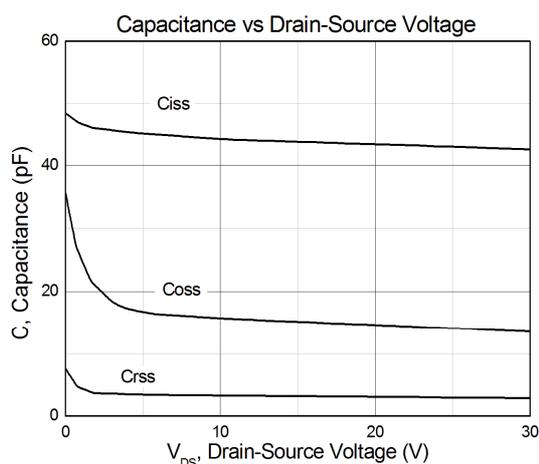


Figure 3

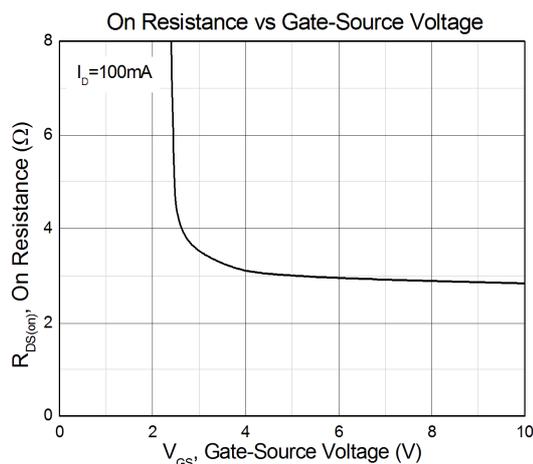


Figure 4

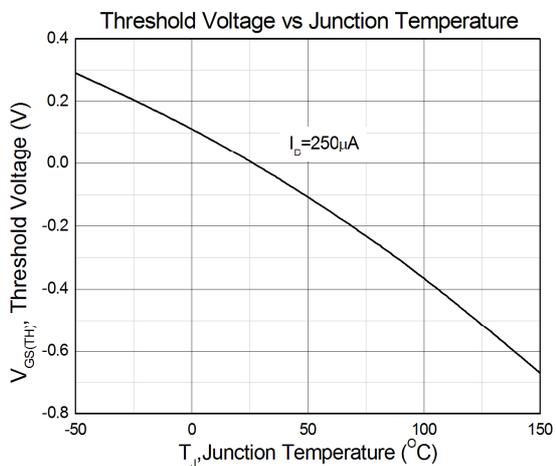


Figure 5

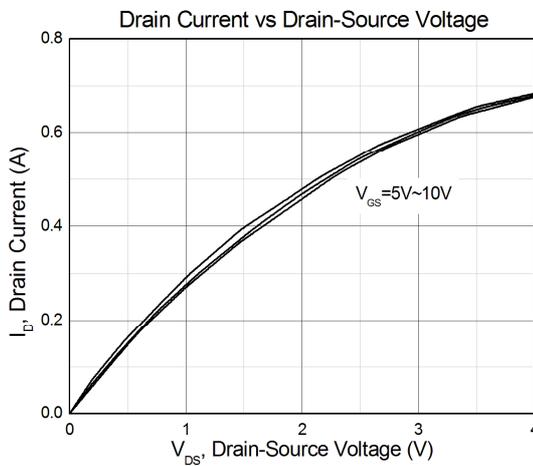


Figure 6



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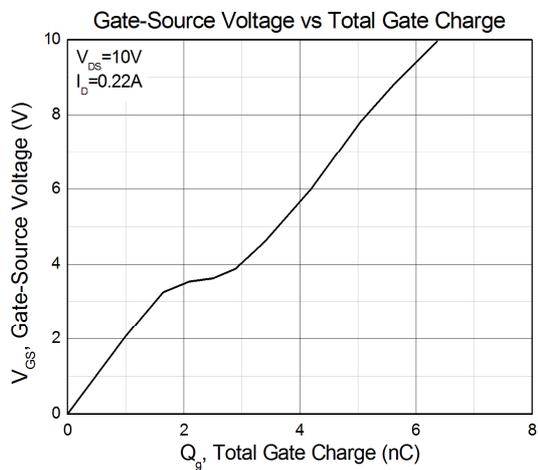


Figure 7

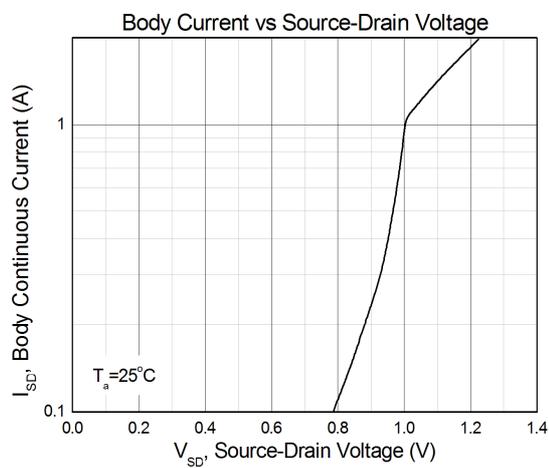


Figure 8



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Test Circuits & Waveforms

Figure 9: Gate Charge Test Circuit

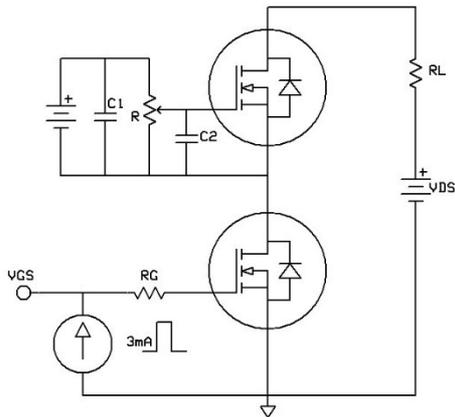


Figure 10: Gate Charge Waveform

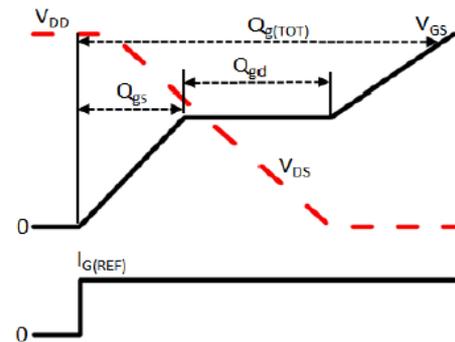


Figure 11: Switching Time Test Circuit

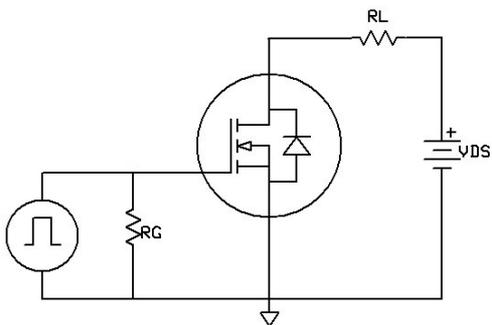
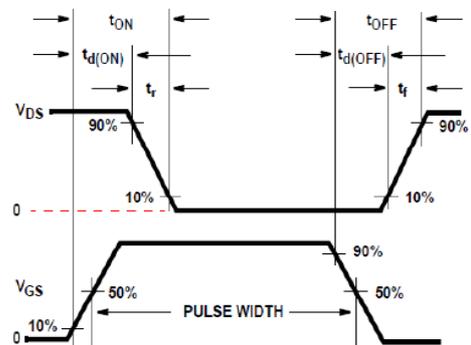
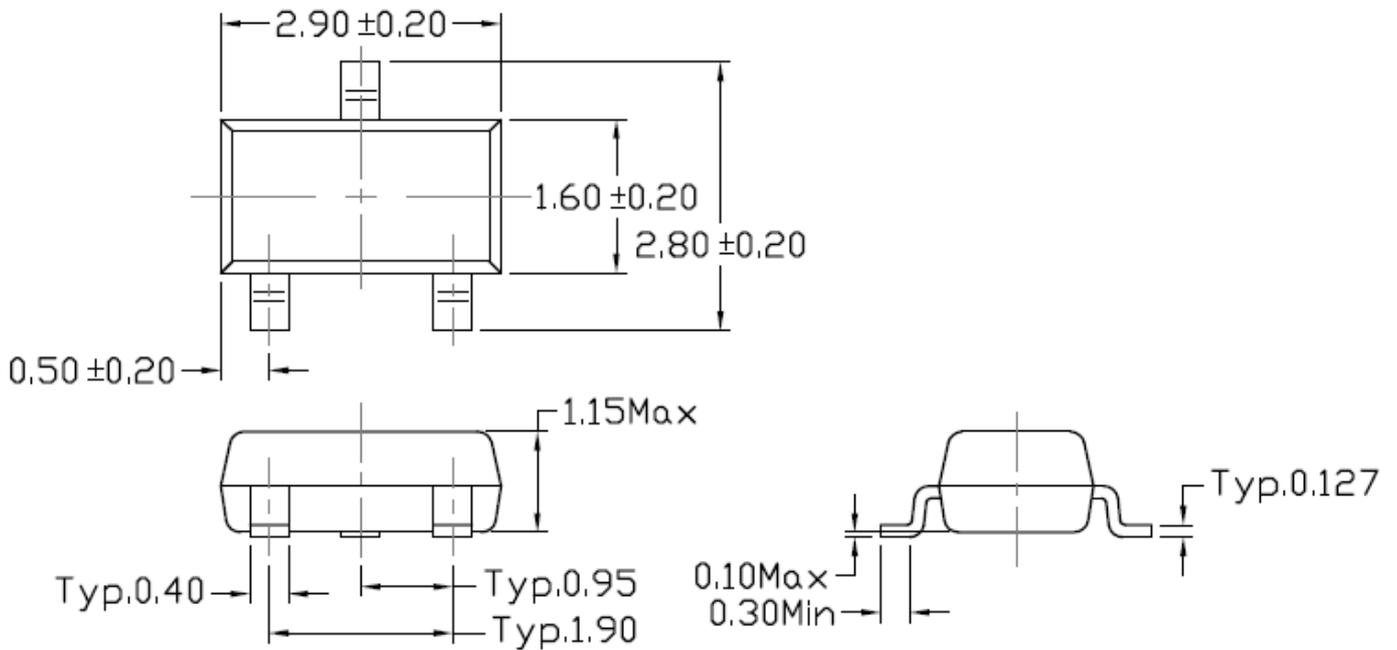


Figure 12: Switching Time Waveform



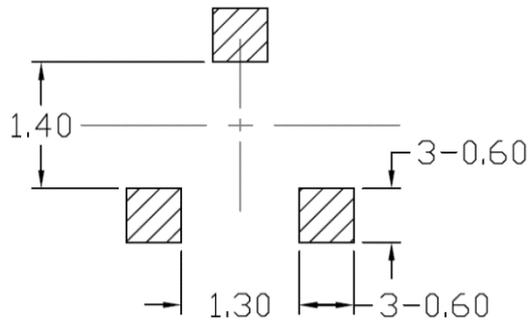


Package Dimension (SC-59)



Note: Dimensions in mm

Recommended pad layout for surface mount leadform



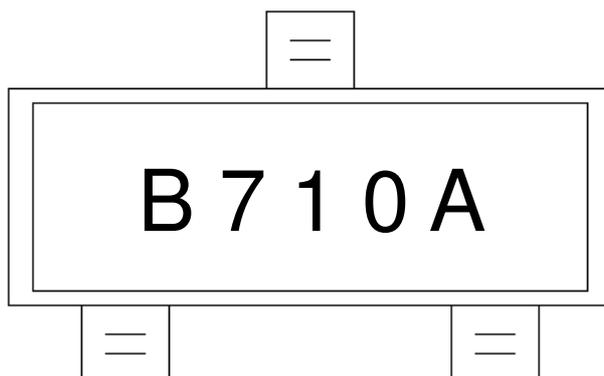
Note: Dimensions in mm



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Marking Information



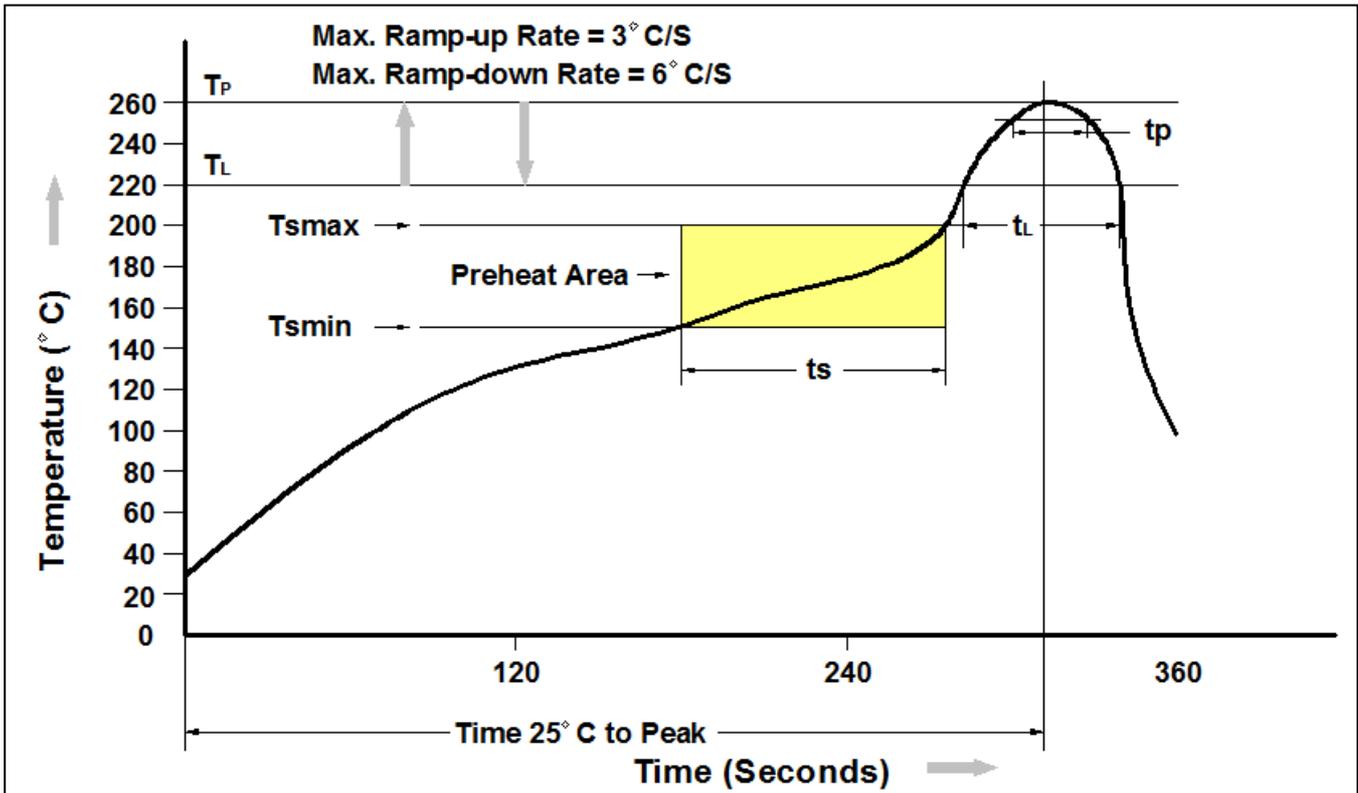
B710A: Device Number

Ordering Information

Part Number	Description	Quantity
CTLM17NS10-R3	SC-59 Reel	3000 pcs



Reflow Profile



Profile Feature	Pb-Free Assembly Profile
Temperature Min. (Tsmmin)	150 °C
Temperature Max. (Tsmmax)	200 °C
Time (ts) from (Tsmmin to Tsmmax)	60-120 seconds
Ramp-up Rate (tL to tP)	3 °C/second max.
Liquidous Temperature (TL)	217 °C
Time (tL) Maintained Above (TL)	60 – 150 seconds
Peak Body Package Temperature	260 °C +0 °C / -5 °C
Time (tP) within 5 °C of 260 °C	30 seconds
Ramp-down Rate (TP to TL)	6 °C/second max
Time 25 °C to Peak Temperature	8 minutes max.



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